

## Abstract

We report on the low-temperature study of thick amorphous  $Y_xSi_{1-x}$  films. In these disordered thin films, transport properties are governed by the interplay between localization, Coulomb interactions and superconductivity. We have studied the temperature dependence of the resistance as a function of the stoichiometry of the alloy. We have determined a preliminary phase diagram for the 3D  $Y_xSi_{1-x}$  alloy. Besides that, on the insulating side, our preliminary results indicate a strong electron-phonon decoupling, which could be the signature of many-body localized states in this system.

## Conclusions

- Our films are homogeneous both in composition and thickness, with a film roughness of about 4 Å.
- Thick amorphous  $Y_xSi_{1-x}$  films can exist under various states - superconducting, metallic and insulating.
- With a weak electron-phonon coupling,  $a-Y_xSi_{1-x}$  could be an interesting material to probe this theoretically-predicted new state and possibly evidence a finite-temperature insulator<sup>[2]</sup>.

## Major Questions!

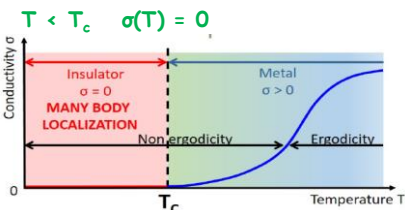
### How low is $Y_xSi_{1-x}$ 's specific heat capacity $C_v$ ?

Studies on amorphous  $Nb_xSi_{1-x}$  films have shown that the specific heat is very important at very low temperature due to the nuclear specific heat in this compound<sup>[1]</sup>.  $Y_xSi_{1-x}$  films should have a lower specific heat which makes it a very promising candidate for thermometric applications.

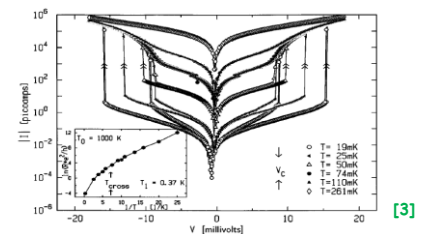
### Many-Body Localization (MBL)

MBL is a new theoretically predicted electronic states, where disorder and Coulomb interactions give rise to a collective mode corresponding to a finite temperature insulator. Electron-phonon decoupling is a requirement for this state to emerge<sup>[2]</sup>.

Thus,

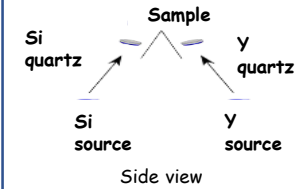


### Strong electron-phonon decoupling



## Sample

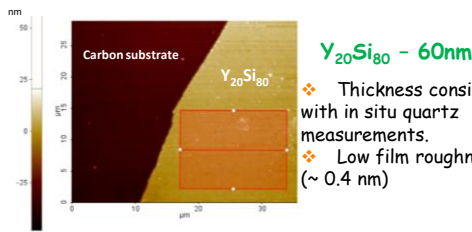
Schematic representation of the e-gun co-deposition process.



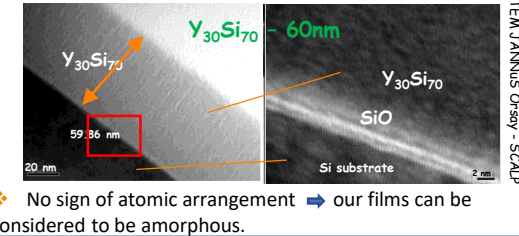
- Under ultrahigh vacuum by e-gun co-deposition.
- $x \in [5, 32]$  %
- Thicknesses  $\in [30, 60]$  nm
- In-situ control of  $x$  & thickness by pairs of quartz

## Sample homogeneity & morphological structure

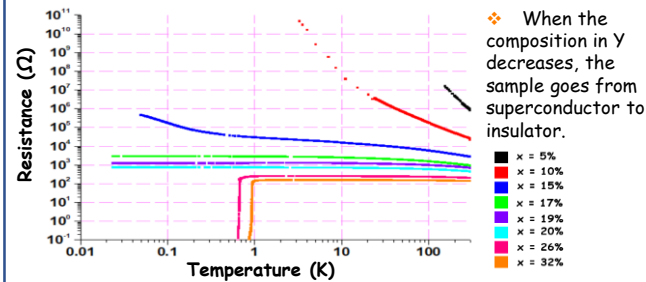
### Atomic Force Microscopy (AFM)



### Transmission Electron Microscopy (TEM)

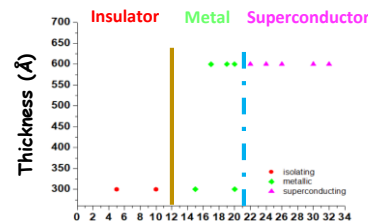


## Transport measurements R(T)

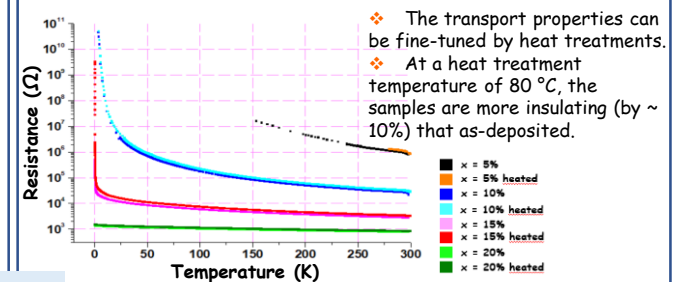


When the composition in Y decreases, the sample goes from superconductor to insulator.

## Preliminary 3D phase diagram



## Effects of heat treatment on the disorder



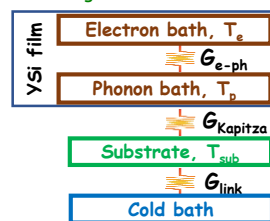
The transport properties can be fine-tuned by heat treatments. At a heat treatment temperature of 80 °C, the samples are more insulating (by ~10%) than as-deposited.

## Results obtained

### Weak electron-phonon coupling

At high electrical power, electrons can thermally decouple from phonons.

Schematic diagram of the hot electron model



Heat-balance equation:

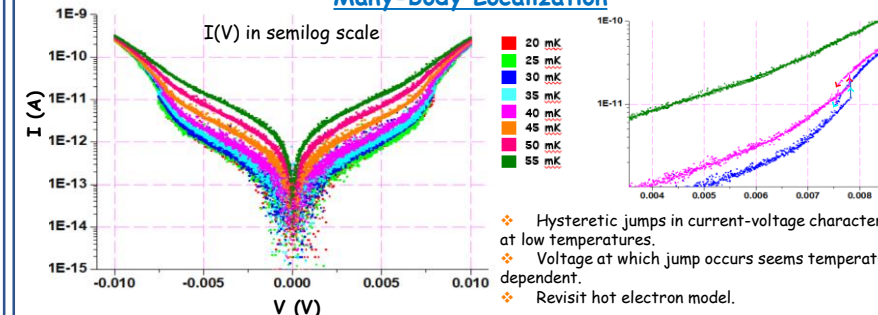
$$P = \Gamma_{e-ph} \Omega (T_{el}^5 - T_{ph}^5) \quad [3]$$

$$\Gamma_{e-ph} \approx 6 - 8 \times 10^{-2} n W / \mu m^3 . K^5 \quad \text{for } T \leq 50 \text{ mK}$$

$$\Gamma_{e-ph} \approx 0.15 n W / \mu m^3 . K^5$$

Weaker than values in  $Nb_xSi_{1-x}$

### Many-body Localization



- Hysteretic jumps in current-voltage characteristics at low temperatures.
- Voltage at which jump occurs seems temperature-dependent.
- Revisit hot electron model.

## Future works

- Complete the first phase diagram (thickness, x).
- Establish how the electron-phonon decoupling evolves with the temperature.
- Systematic R(T) measurements at lower thickness and with heat treatment.
- Morphological characterizations with and without heat treatment.

## References

- Couches minces d'isolant d'Anderson application à la biométrie à très basse température, Stefanos Marnieros, 1998, [Doctoral thesis, University Paris XI]. <https://www.theses.fr/1998PA112119>
- Possible experimental manifestations of the many-body localization, D. M. Basko, I. L. Aleiner, and B. L. Altshuler Phys. Rev. B 76, 099902 (2007)
- Depinning transition in Mott-Anderson insulators F. Ladieu, M. Sanquer, and J. P. Bouchaud, Phys. Rev. B 53, 973

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